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Monuko du Plessis

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Introduction

The 3rd South African Conference on Sensors, MEMS, and Electro-Optical Systems (SMEOS 2014) was held from 17 to 19 March 2014 in Skukuza, the main rest camp in the Kruger National Park, South Africa, after a very successful SMEOS 2009 and SMEOS 2011. Sensors and Electro-Optical Systems are technologies with many applications worldwide, and are also identified as such by the South African government through the Departments of Science and Technology.

The aim of SMEOS 2014 was to provide a common forum for international researchers and developers to exchange information about their latest research findings, ideas, developments, and applications in all areas pertaining to design, fabrication, and application in the fields of interest to SMEOS 2014. This is a relatively small field of expertise in South Africa and working together with international colleagues is of the utmost importance.

Monuko du Plessis

